

# Reduction techniques of the back gate effect in the SOI Pixel Detector

R. Ichimiya (KEK)\*

for the SOI Pixel collaboration

<http://rd.kek.jp/project/soi/>

## SOI Pixel Collaboration

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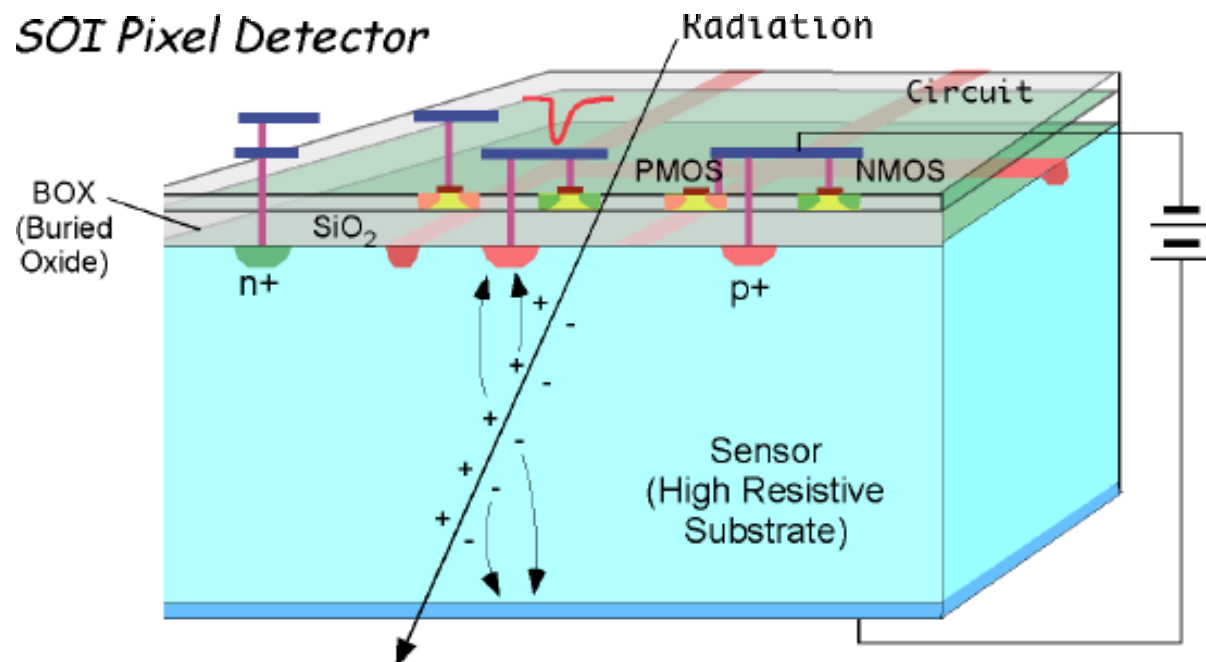
**INFN Padova** : Dario Bisello, Serena Mattiazzo, Devis Pantano, Piero Giubilato

**OKI Semiconductor Co. Ltd.** : K. Fukuda, I. Kurachi, M. Okihara , ....

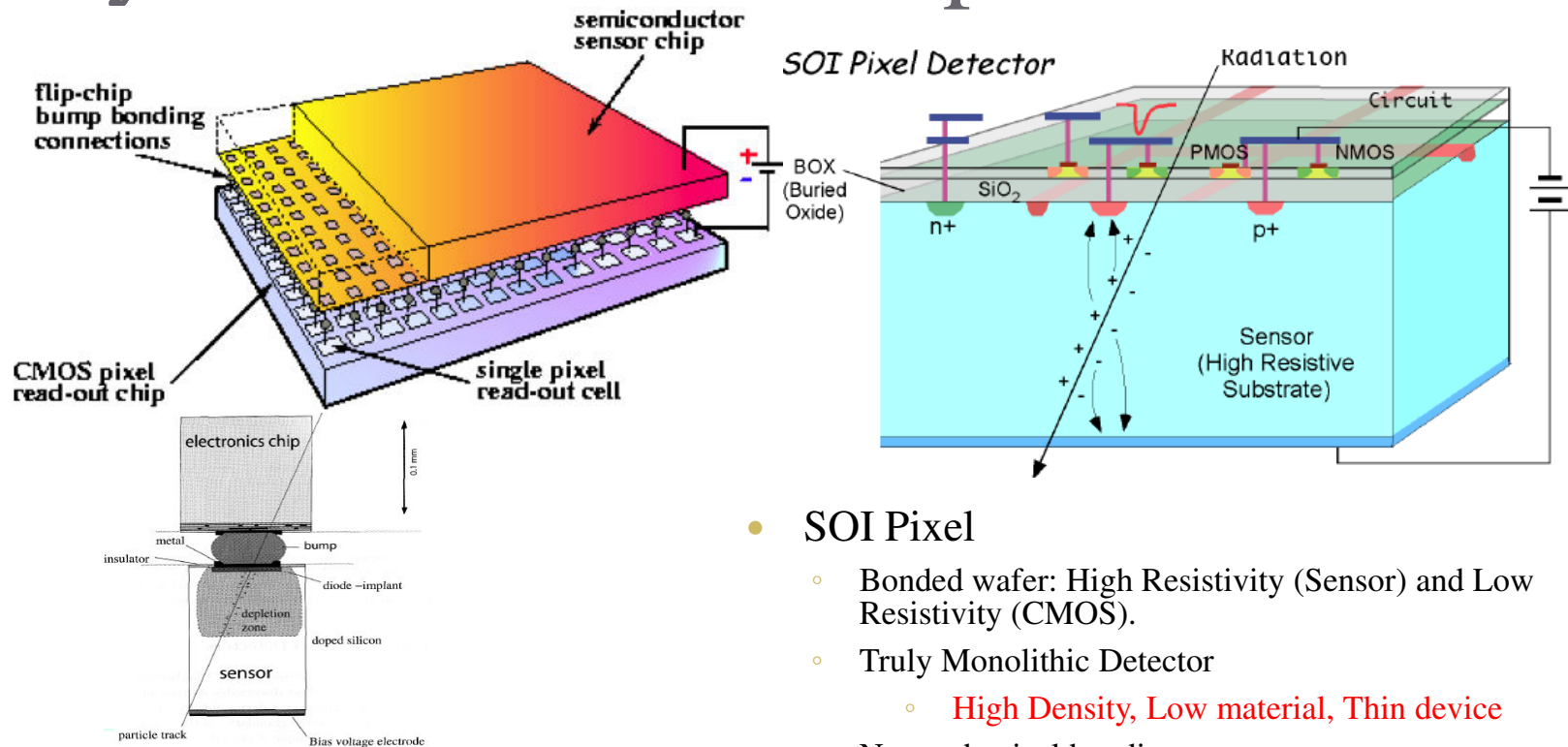
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# Outline

1. SOI technology and SOI pixel detector
2. Pixel Test Results
3. On going R&Ds
4. Summary



# Hybrid Pixel v.s. SOI pixel



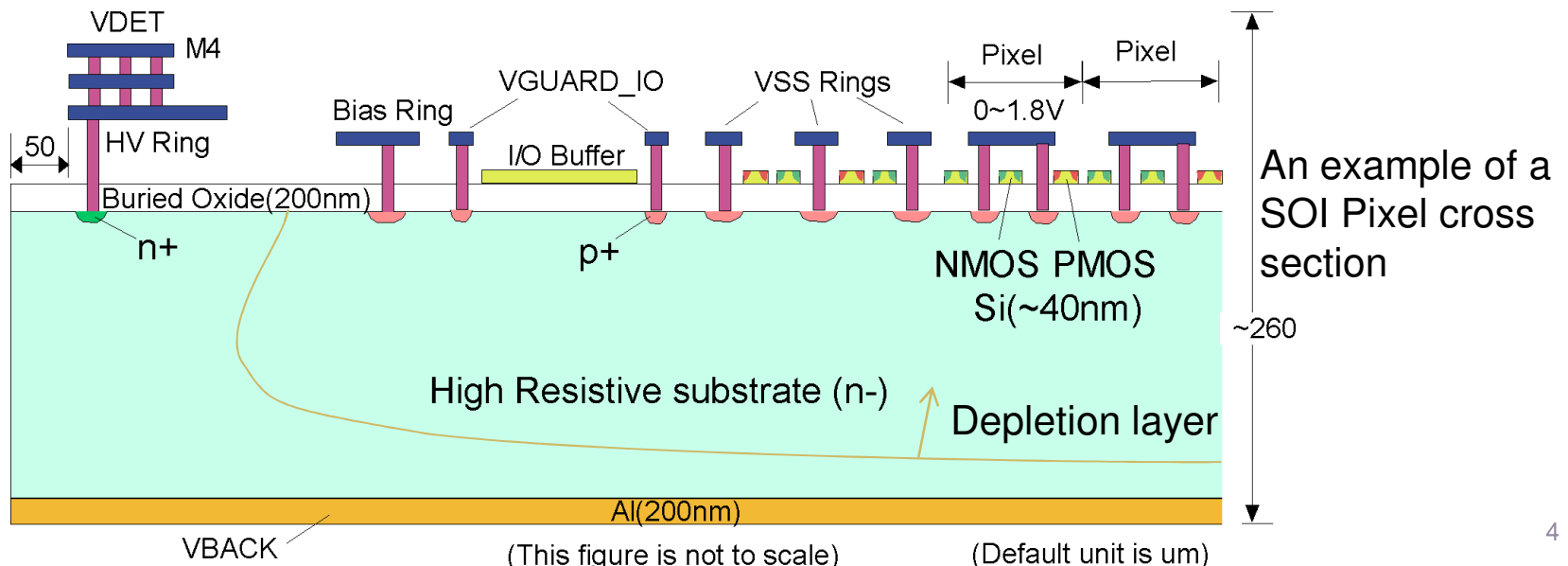
- Hybrid Pixel (conventional pixel detector)
  - Fabricate Sensor and Readout chip individually.
  - Make contacts by bump bonding for each pixel.
  - Granularity is limited (~50um) from bump-bonding fabrication .
  - Speed and Gain reduction by parasitic capacitance.
  - It becomes thick detector by bump-bonding structure.

- SOI Pixel

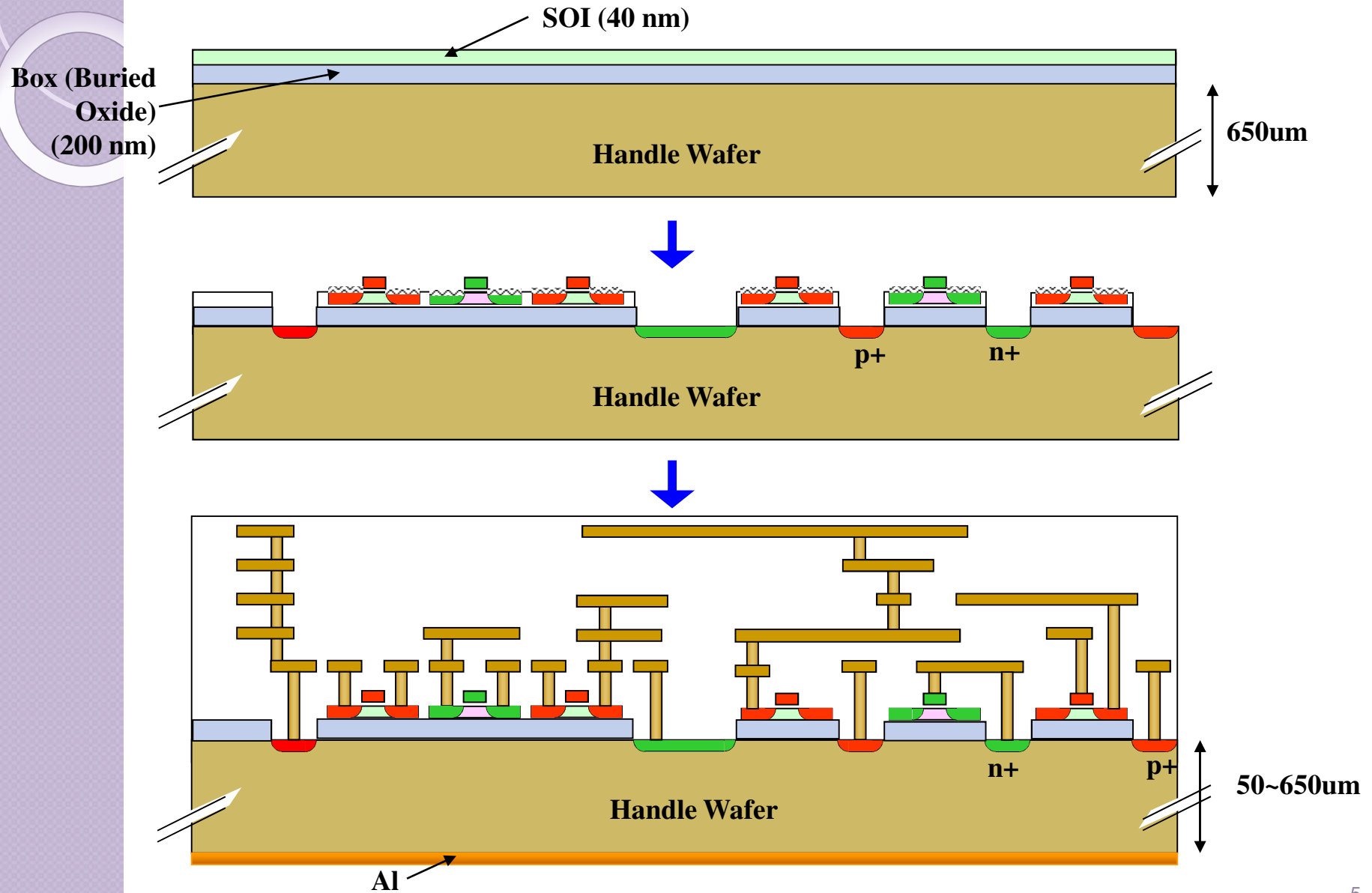
- Bonded wafer: High Resistivity (Sensor) and Low Resistivity (CMOS).
- Truly Monolithic Detector
  - High Density, Low material, Thin device
- No mechanical bonding.
  - High yield, Low cost.
- Fully depleted sensor with small capacitance of the sense node.
  - ~10fF, High gain, Low noise
- Based on Industrial standard technology
  - Cost benefit and scalability.
- No Latch-up, Radiation hardness, Low power.
- Low to High temperature operation (4K-300C).
- ...

# Oki 0.2 $\mu\text{m}$ FD-SOI Pixel Process

Process	0.2 $\mu\text{m}$ Low-Leakage Fully-Depleted SOI CMOS (OKI) 1 Poly, 4 Metal layers, MIM Capacitor, DMOS option Core (I/O) Voltage = 1.8 (3.3) V
SOI wafer	Diameter: 200 mm $\phi$ , Top Si : Cz, $\sim 18 \Omega\text{-cm}$ , p-type, $\sim 40 \text{ nm}$ thick Buried Oxide: 200 nm thick Handle wafer: Cz, $700 \Omega\text{-cm}$ ( <i>n-type</i> ), 650 $\mu\text{m}$ thick
Backside	Thinned to 260 $\mu\text{m}$ , and sputtered with Al (200 nm).

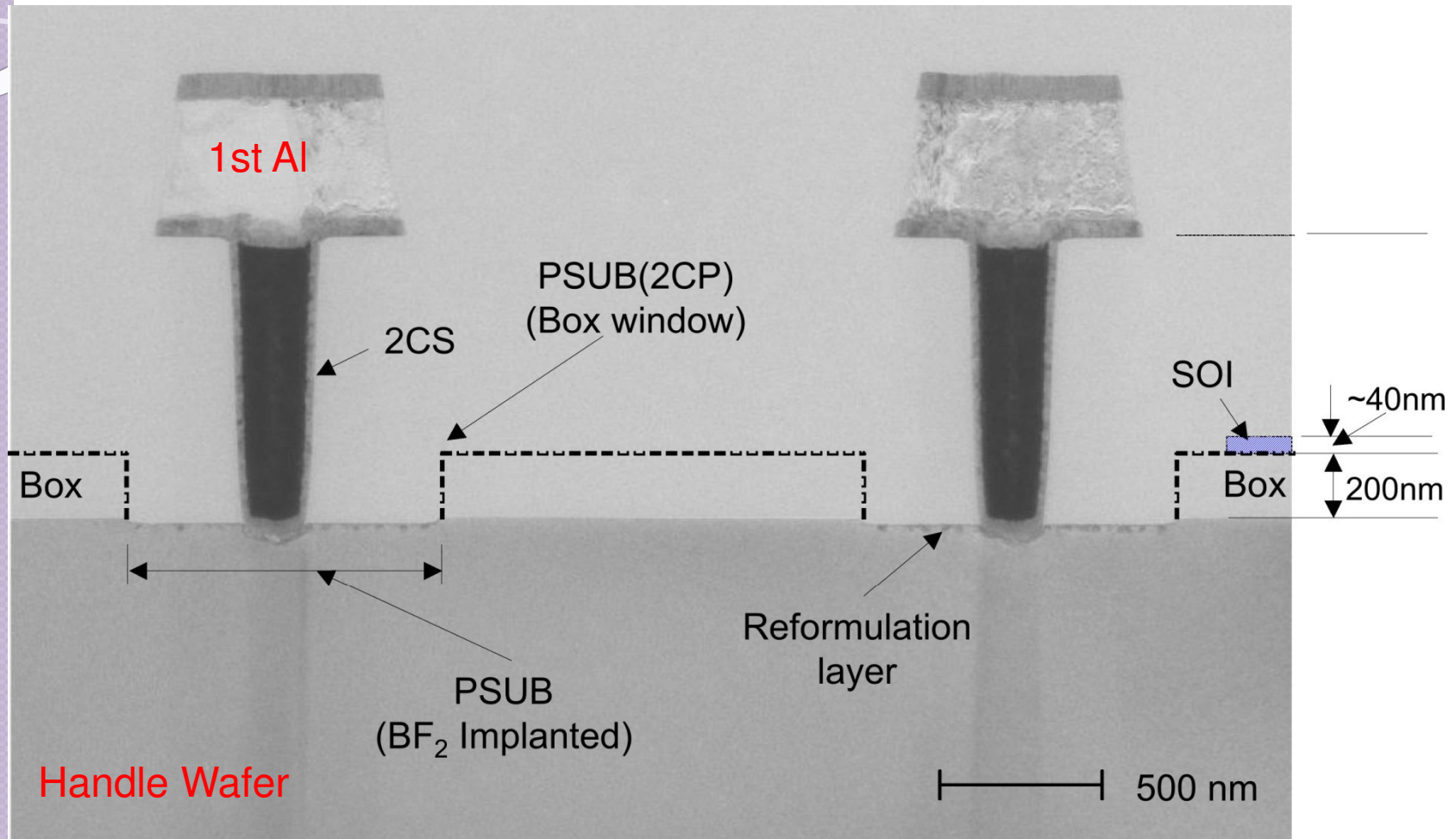


# SOI Pixel process flow

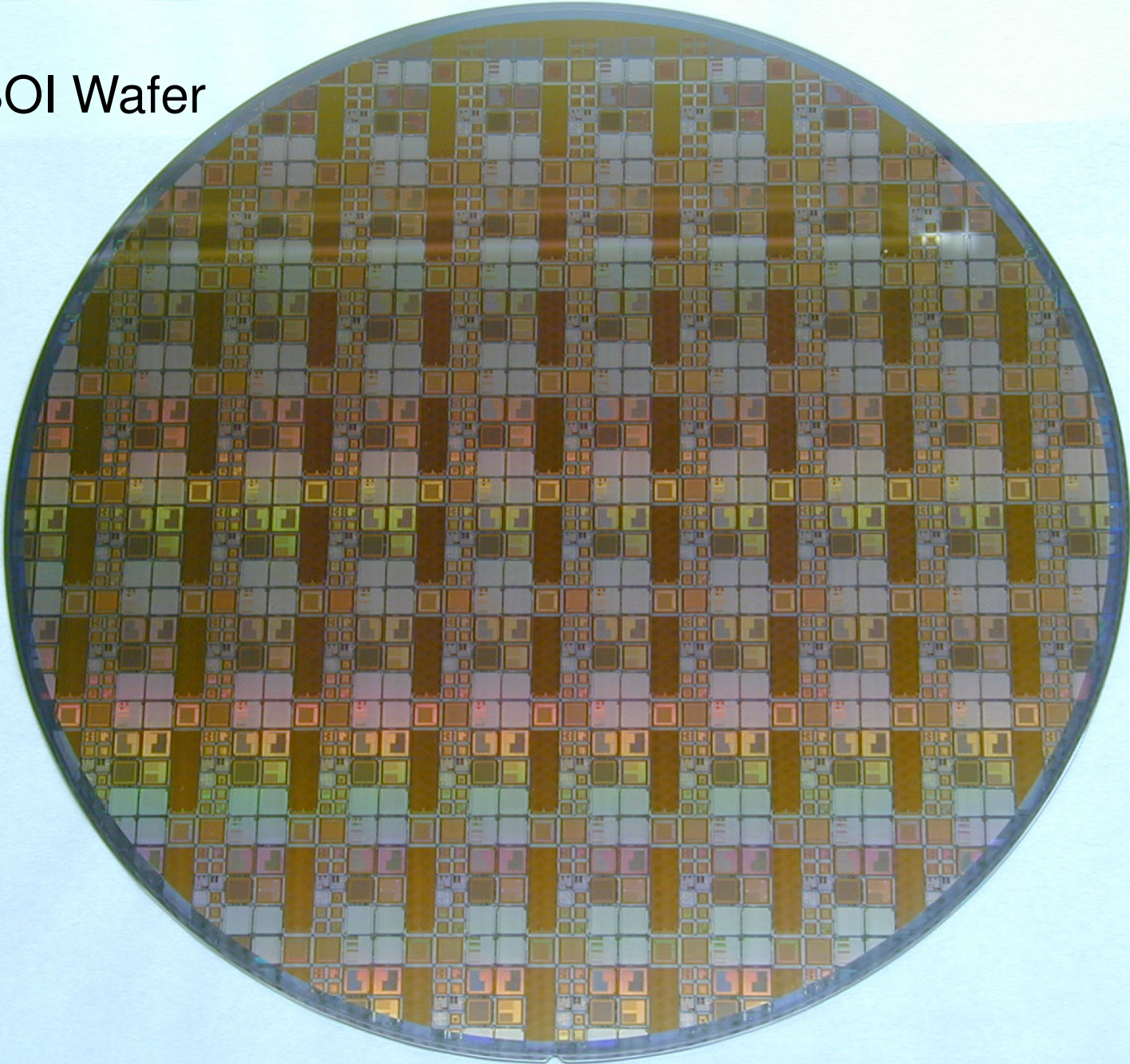




# Metal contact & p+ implant

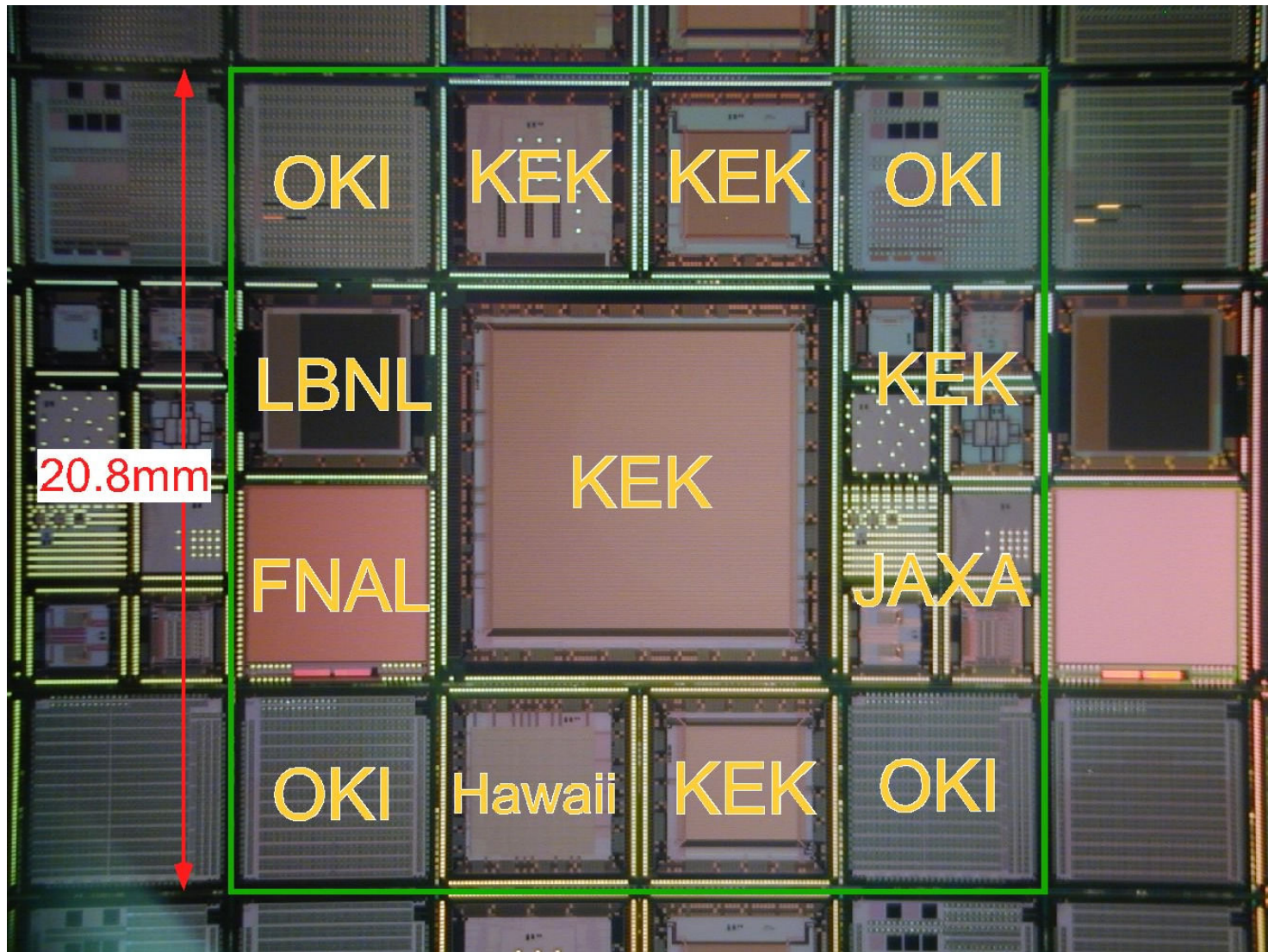


8inch SOI Wafer





# KEK SOI Multi Project Wafer (MPW) run



- 3 MPW runs are scheduled in 2009 FY.
- We welcome your Designs.

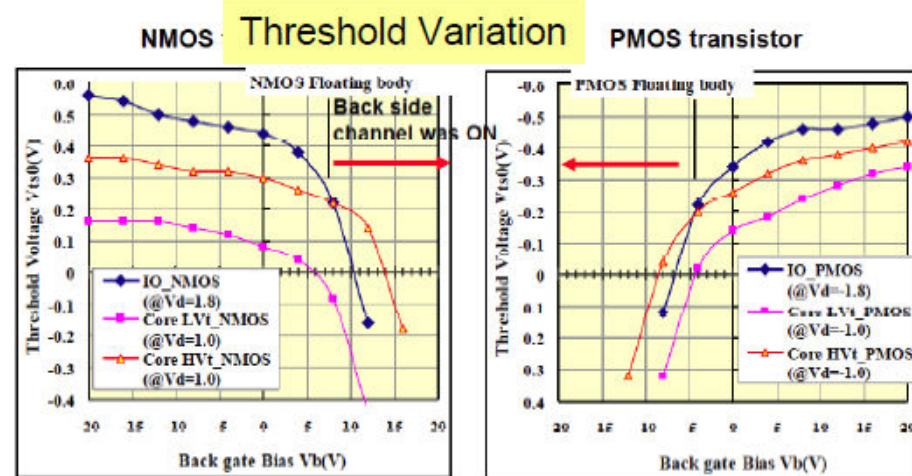
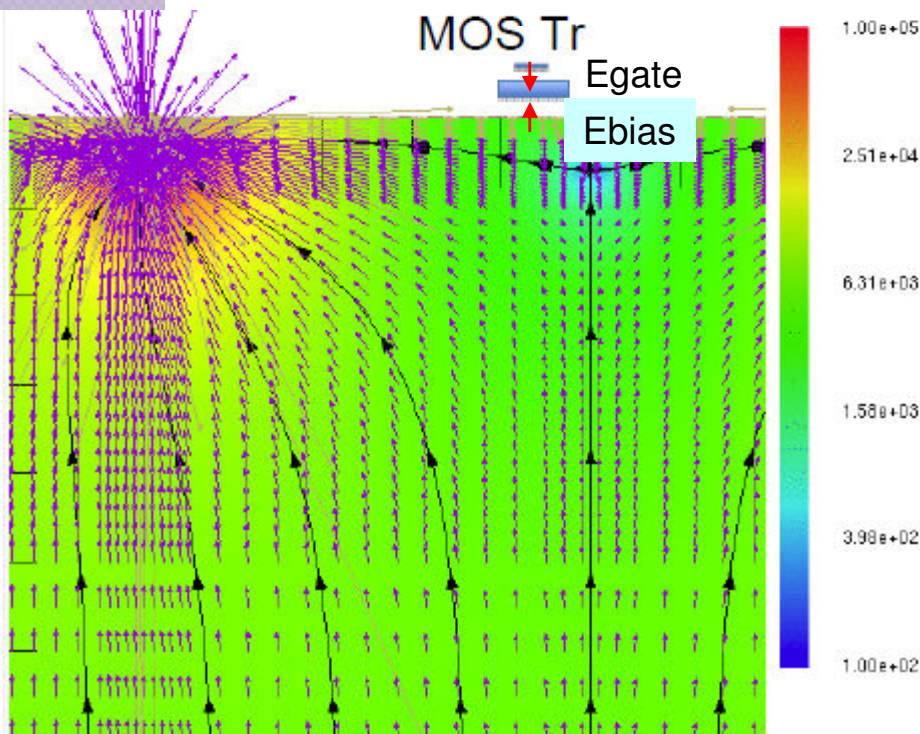


# Back gate effect on SOI pixel

- Transistors locate very close ( $\approx 200\text{nm}$ ) to the Sensor where high voltage applied.
- Substrate (Sensor) Voltage acts as Back Gate in a MOS transistor, and change its threshold voltage.

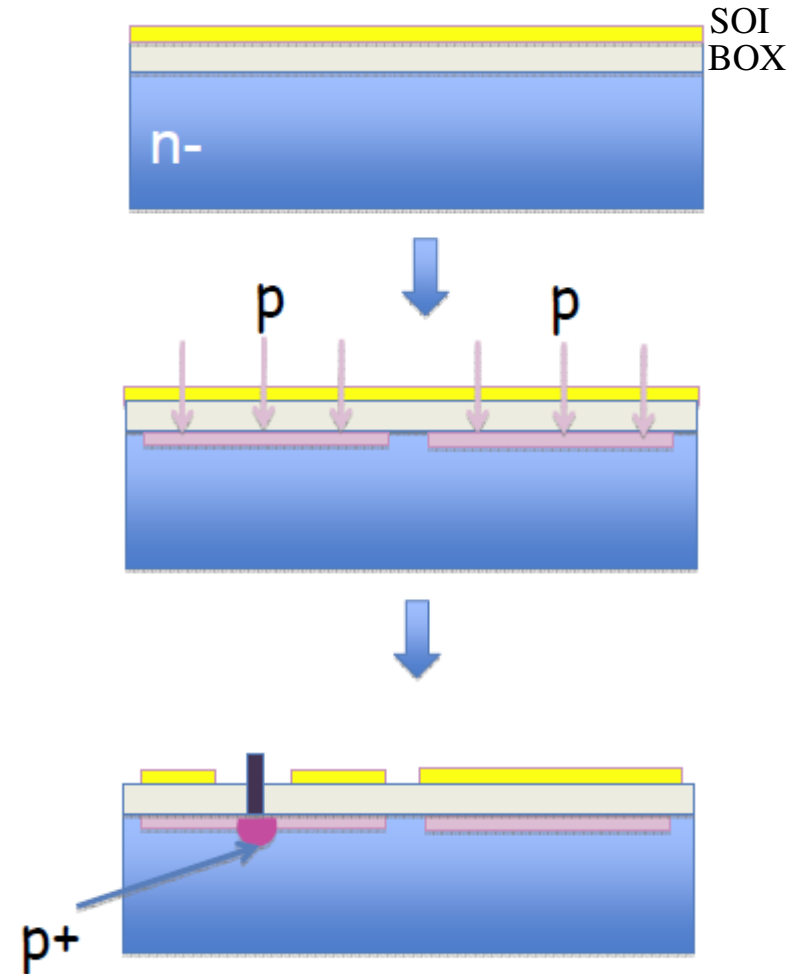


- Unless we solve this dilemma, we cannot operate this detector with fully depleted condition.



# Buried p-well technology

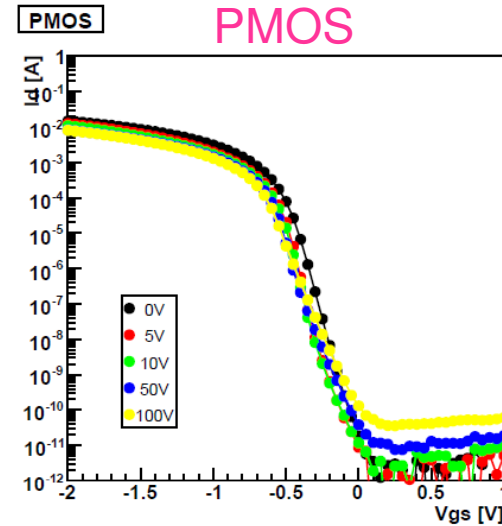
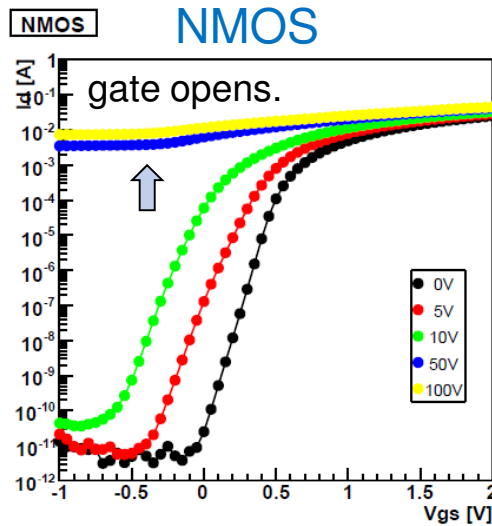
- In order to **shield** the transistors from **electrical field** from the Sensor,
- Implant **p-Well** through SOI and BOX layer. (buried p-Well)
- Benefits:
  - Suppress back gate effects.
  - Reduce electric field around p+ sensor.
  - Less electric field in BOX to improve radiation hardness.



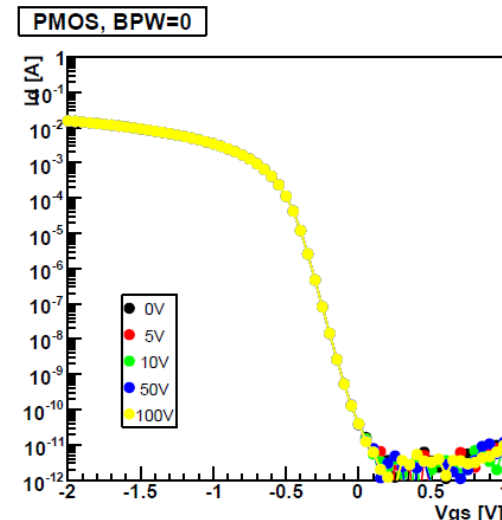
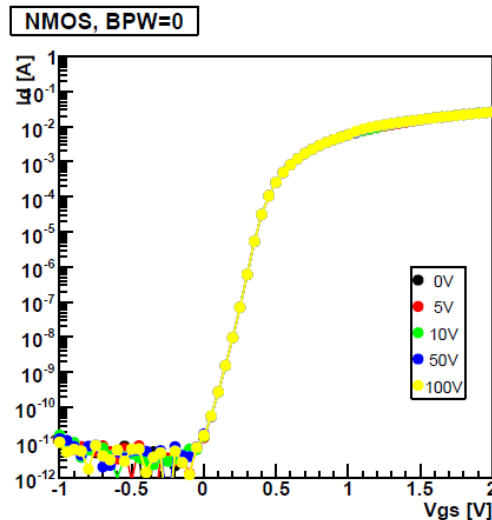
Essential and breakthrough technology to overcome the back gate effect.

# $I_d - V_{gs}$ curve under bias voltage applied

w/o BPW



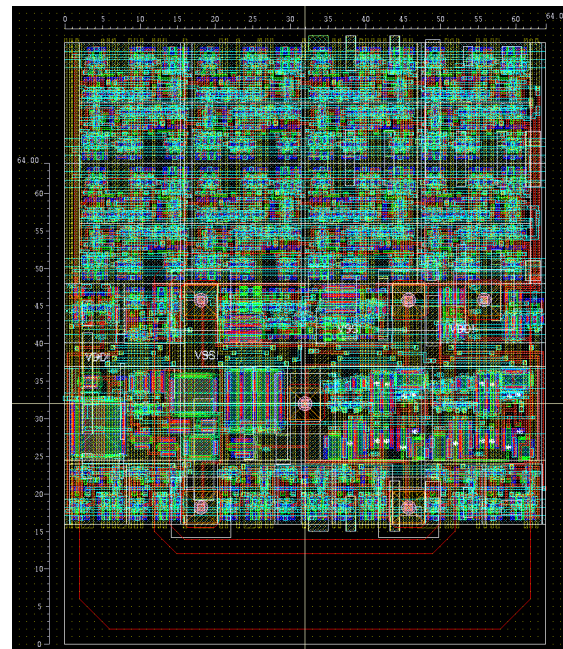
w/ BPW  
=0V



- Back gate effect is effectively suppressed by BPW even at 100V bias voltage.

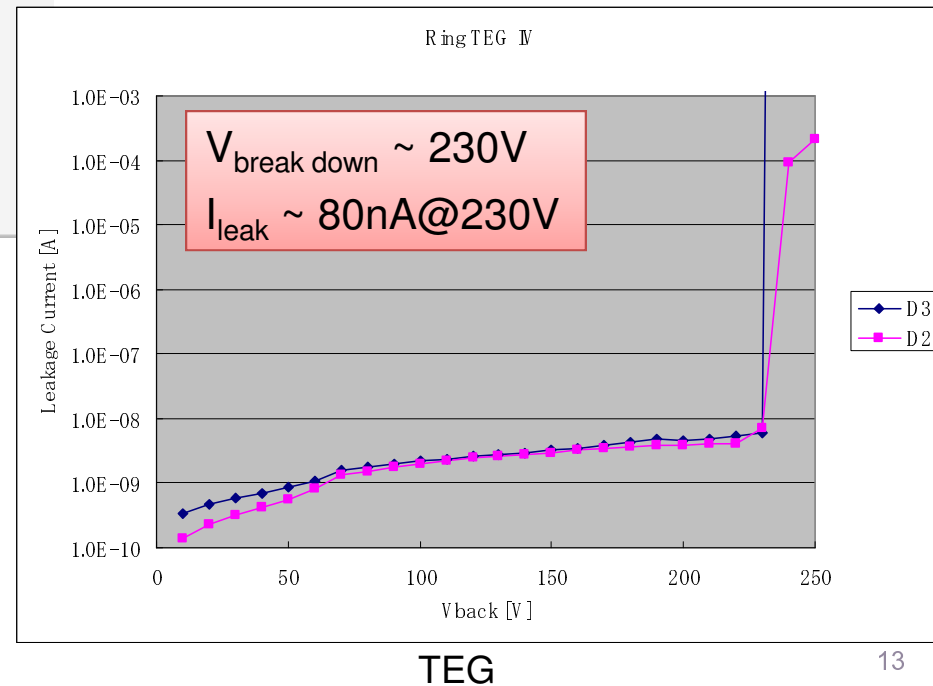
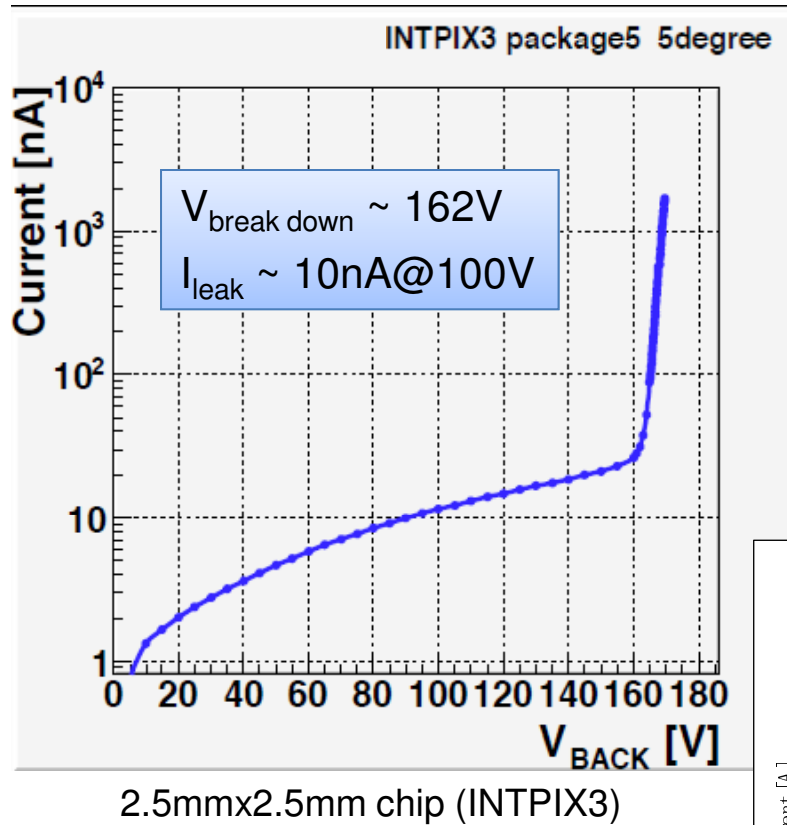


# Pixel test Results

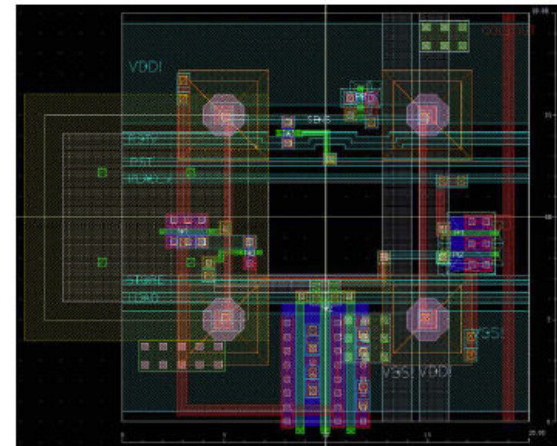
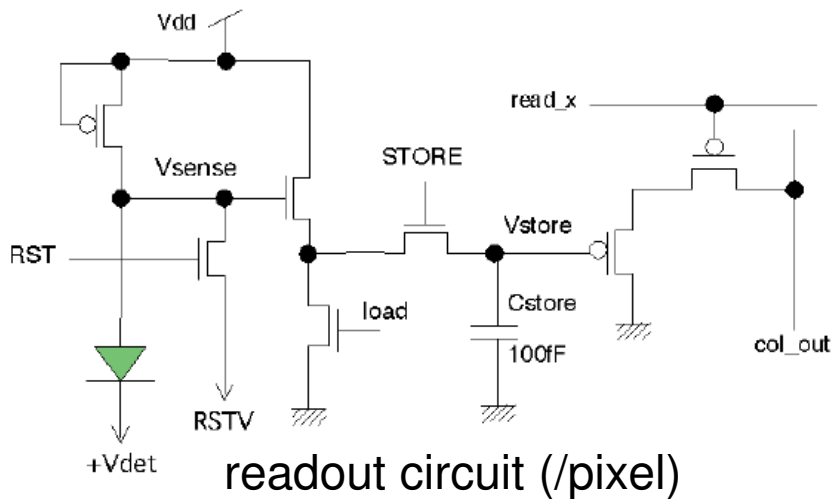
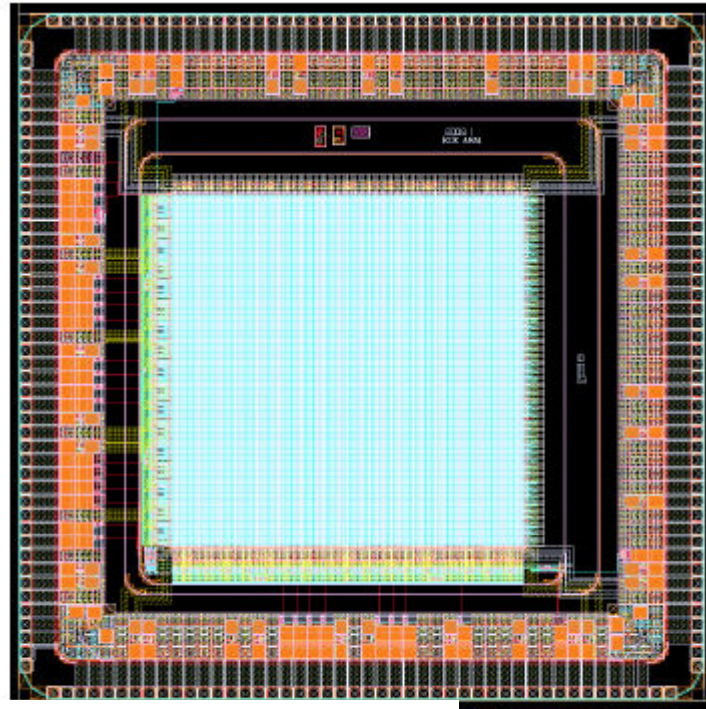


CNTPIX3 pixel

# Breakdown voltage & leak current



# Integration type Pixel (INTPIX)



20µm x 20µm pixel



# SOI pixel Laser Images

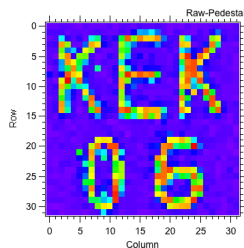
INTPIX2

2008

2.56 mm

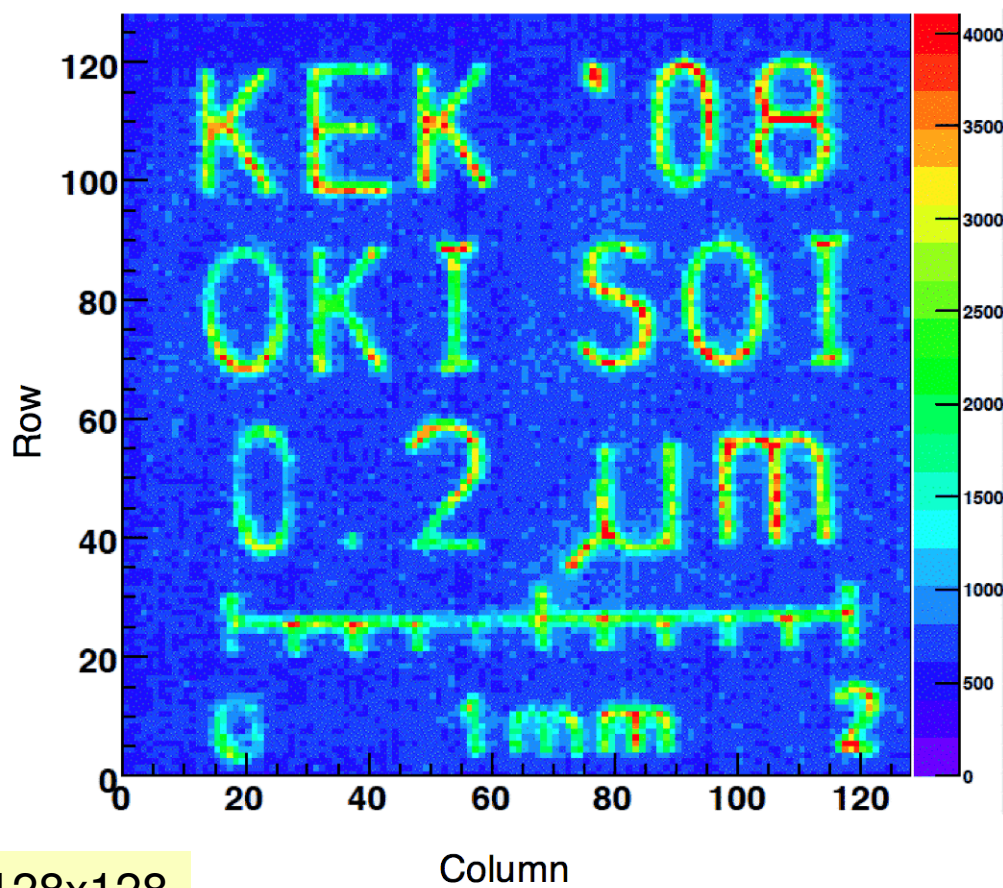
2006

0.64 mm



32x32

with Plastic mask

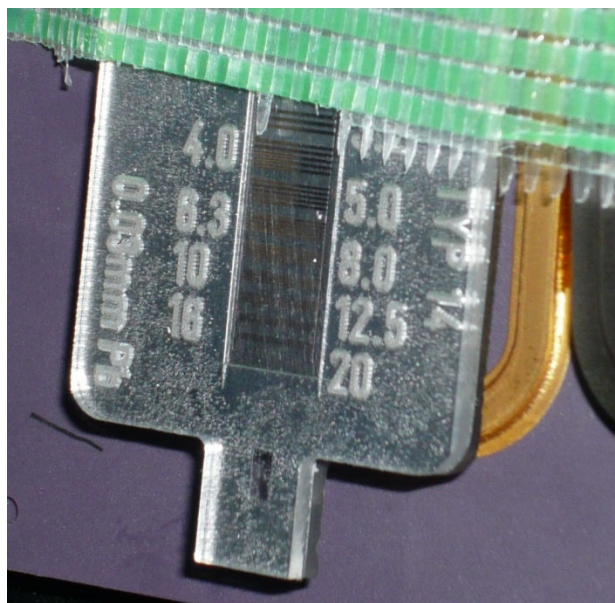


128x128

# X-ray Irradiation test

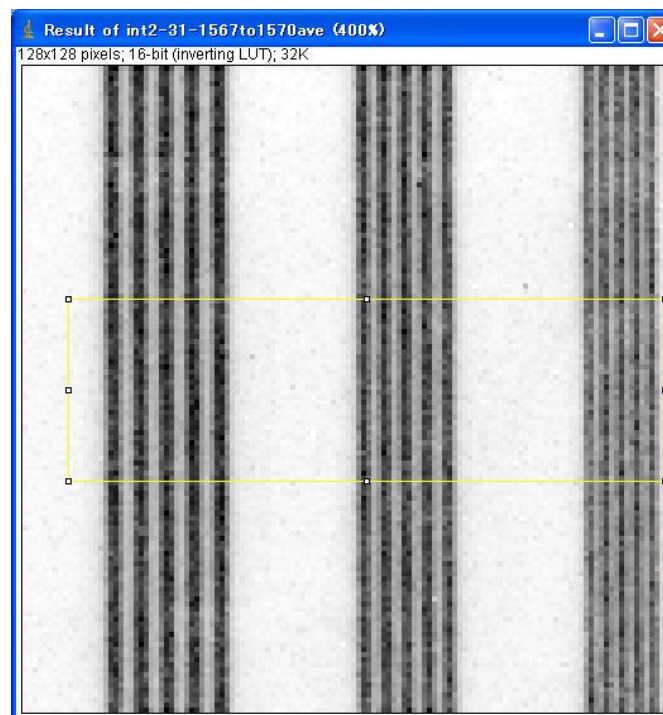
INTPIX2  
(pixel size=20 $\mu$ m $\times$ 20 $\mu$ m)

- X-ray generator: Rigaku FR-D
- Target: Cu (Cu K $\alpha$  ~8keV)
- Power: 30-35 kV, 10-30mA
- Intensity:  $\sim 10^4$  photons/pixel/sec @30kV, 10mA

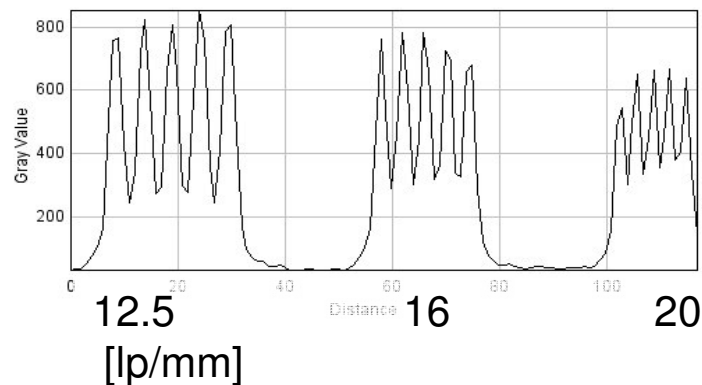


X-ray Test Chart

25  $\mu$ m Slit is well separated.



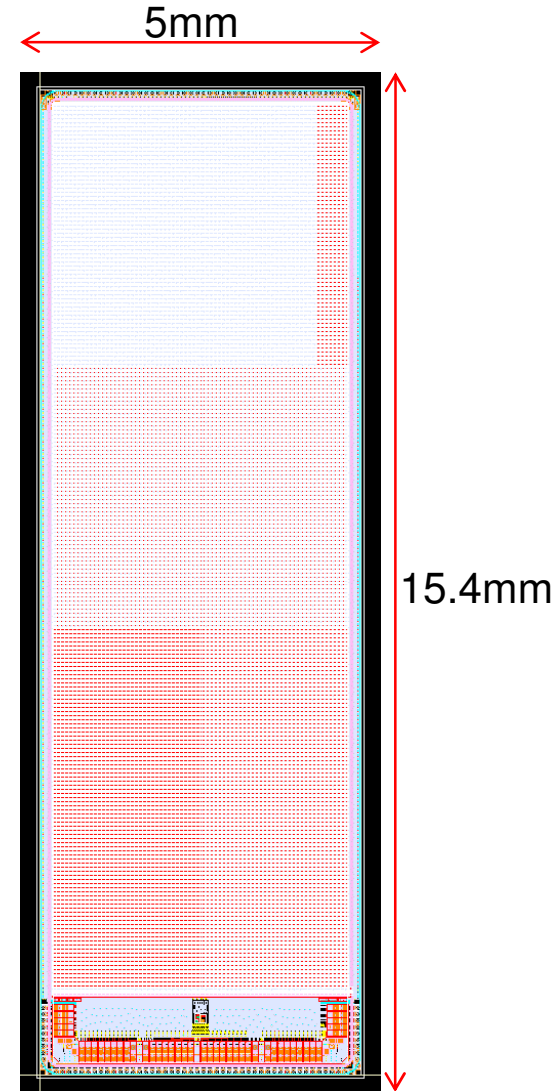
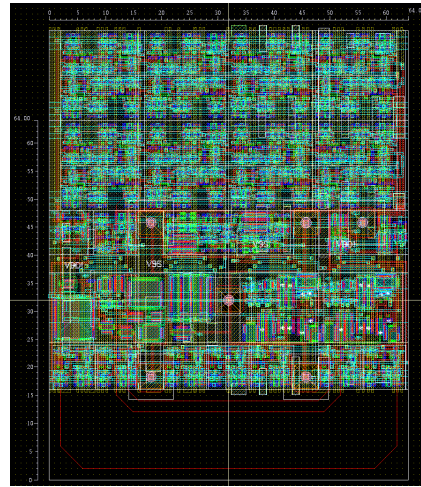
slit w=25 $\mu$ m



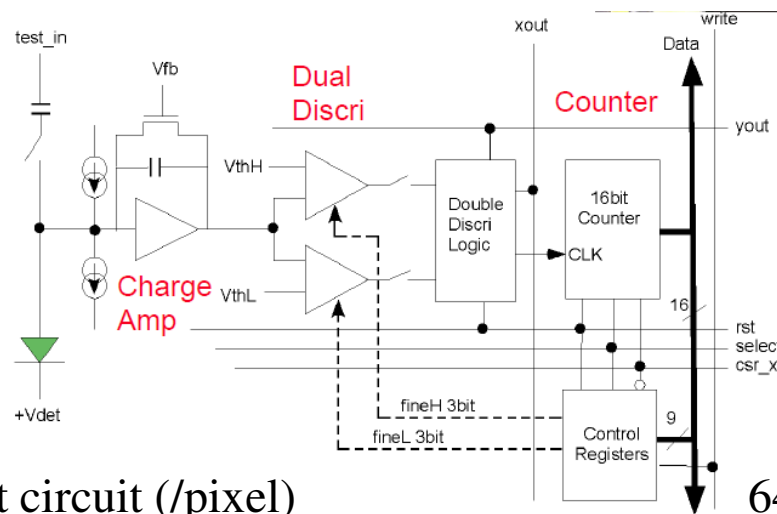


# Counting type Pixel (CNTPIX)

- Discriminated signal is counted by a 16-bit counter.
- Energy window can be set in each pixel.



CNTPIX3  
(row:218 x column:72)

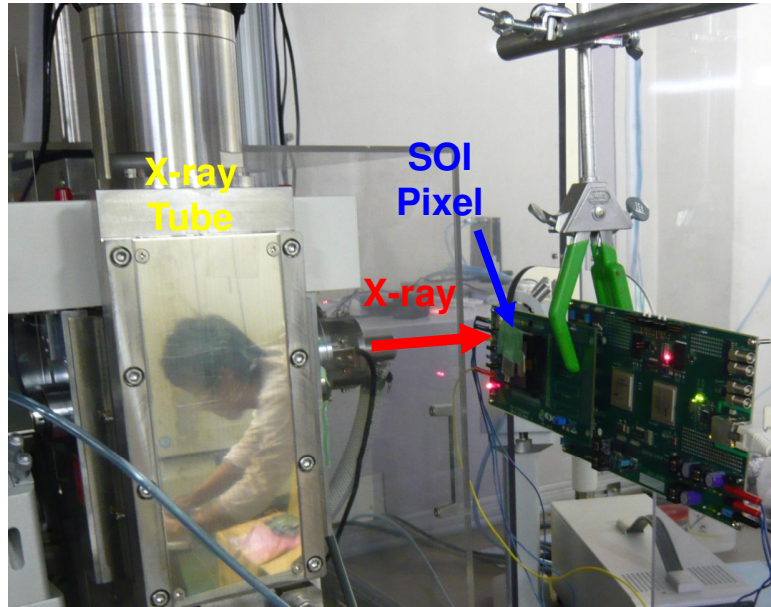


Readout circuit (/pixel)

64x64  $\mu\text{m}^2$

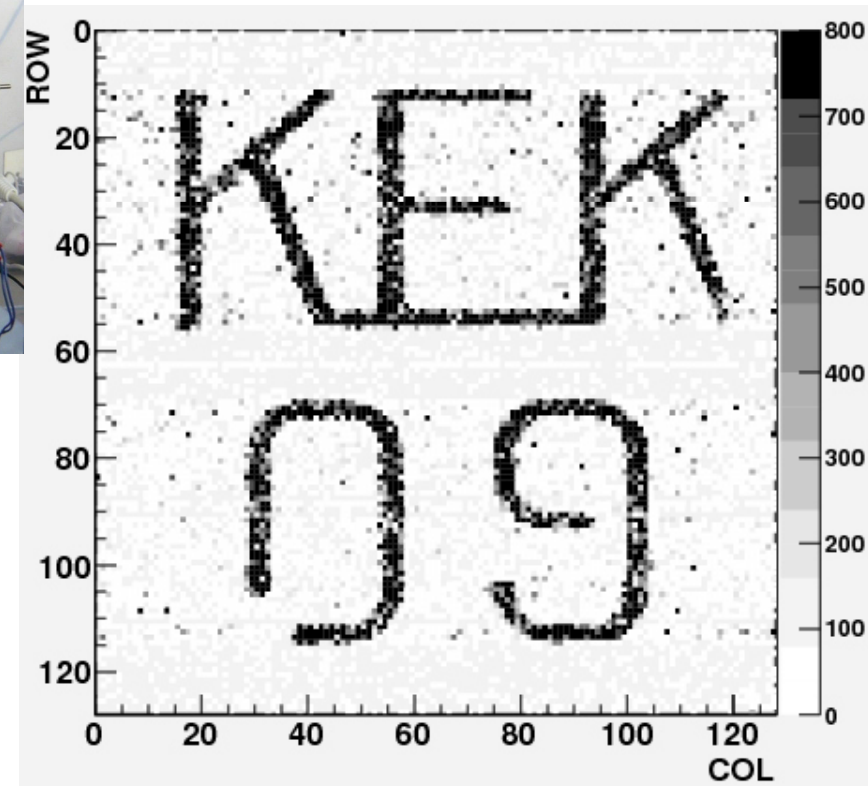


# SOI pixel Laser Image (CNTPIX)



- Image taken by X-ray irradiation

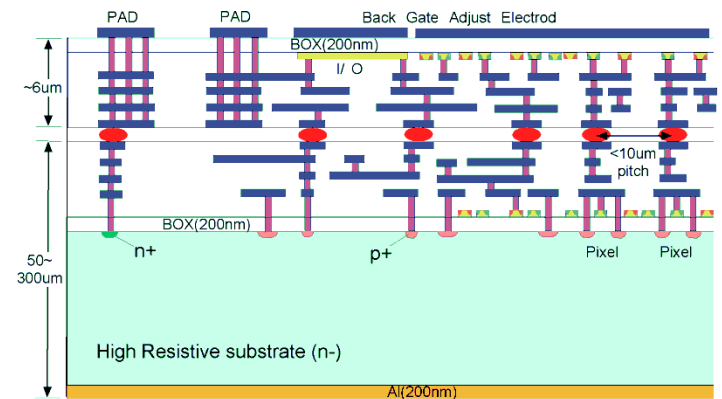
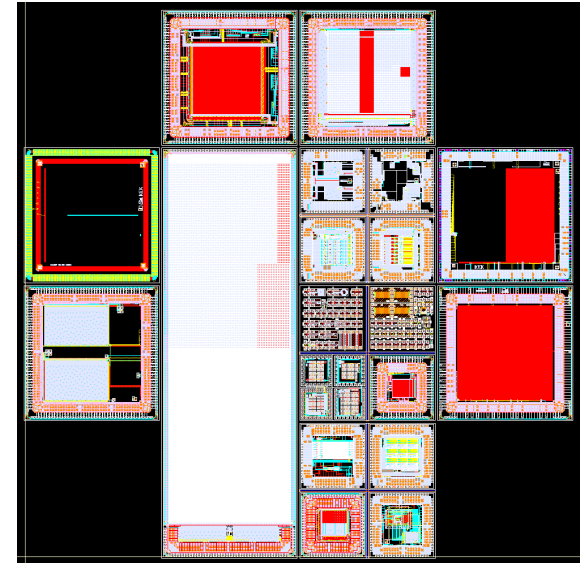
40kV-40mA  
Subtracted by background count  
Integration time 64ms / vth 350mV  
Vback=15V



Counter works well

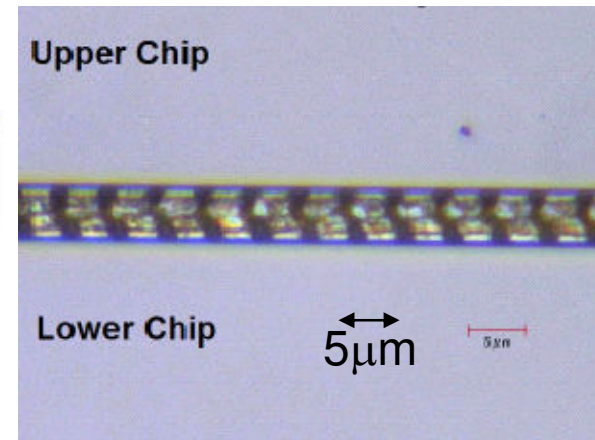
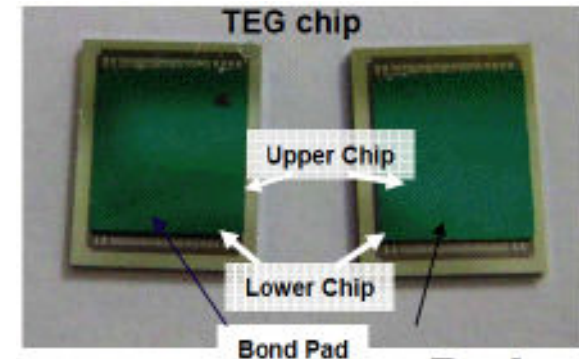
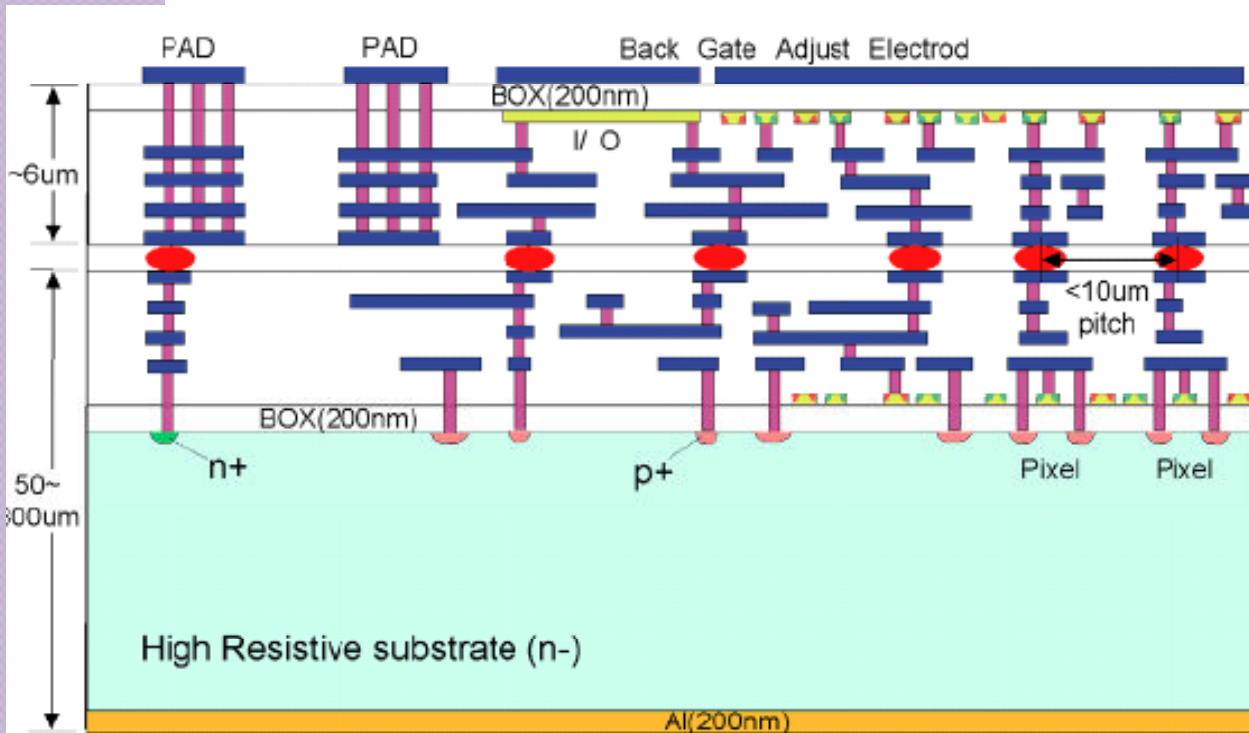
# On going R&Ds

- Process improvement:
  - High radiation tolerance, high resistivity wafer, deeper depletion layer, wafer thinning,...
- Larger sensitive area; stitching,...
- **3D integration**



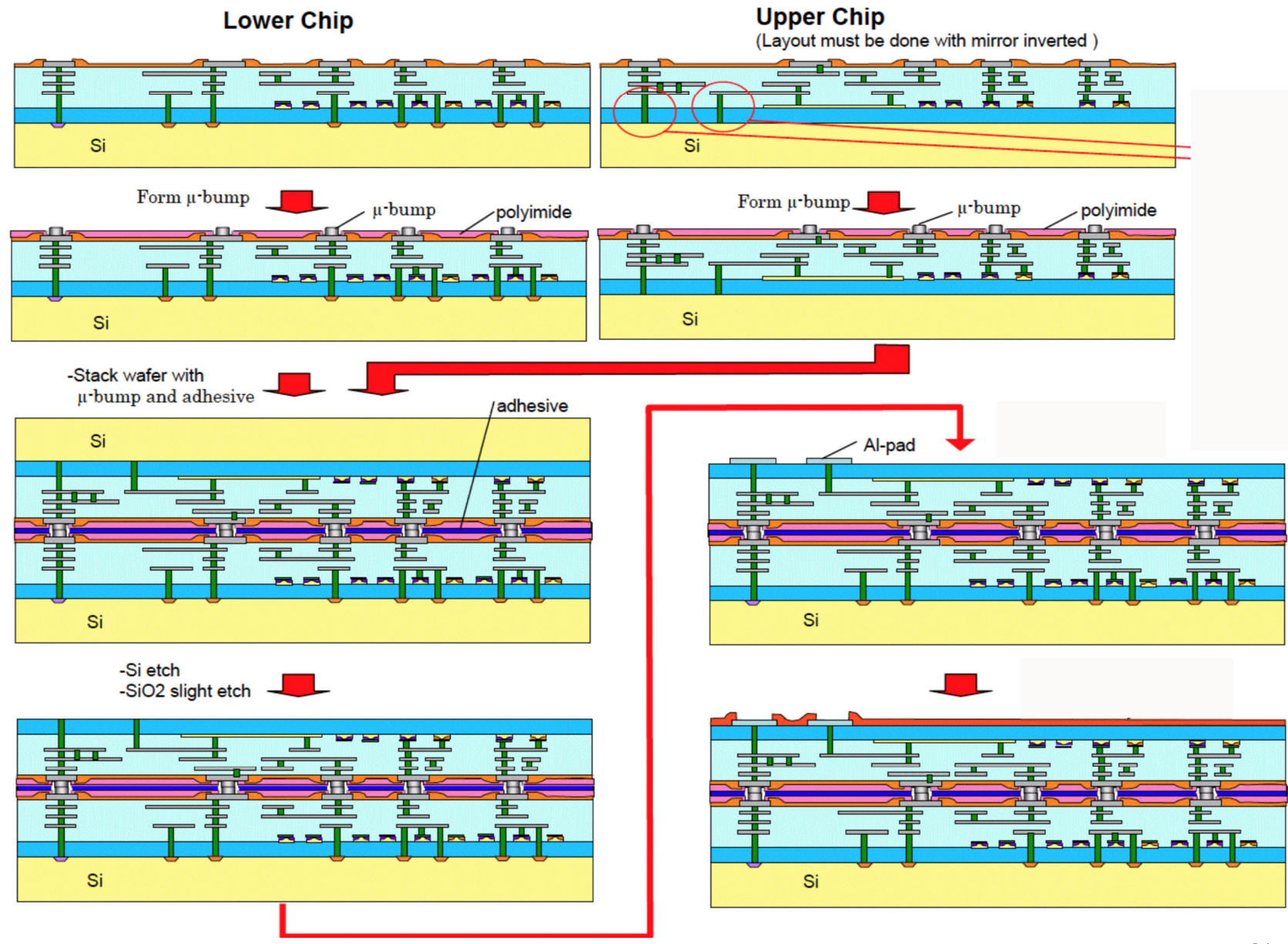
# 3D Integration with ZyCube $\mu$ -bump

- Use ZyCube Co. Ltd.(Japan)  $\mu$ -bump bonding ( $\sim 5\mu\text{m}$  pitch) technology.
- This enables
  - Dead-Area Free Large pixel detector.
  - ADC integration,...





(1) Stack Process Flow (after finishing wafer process)



# Summary

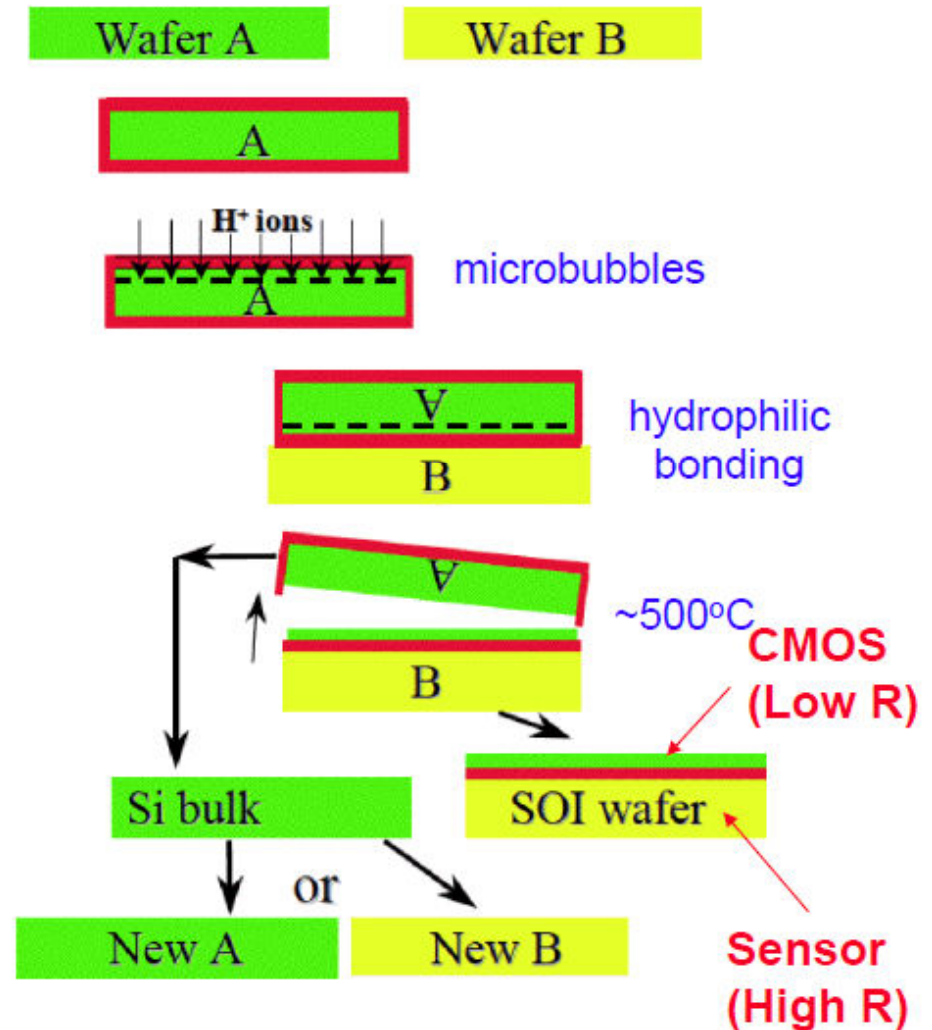
- The SOI Pixel detector is a unique and attractive **monolithic pixel detector**. It features such as high speed, low material budget, high resolution,...
- As SOI pixel detector uses **commercial mass production process**, it has cost benefits and scalability. (Moore's Law)
- We have overcome the back gate effect (electrical field of bias voltage changes transistor's threshold voltage) by Buried p-well (BPW) implantation. **Now SOI pixel detector becomes practical detector.**
- We have confirmed **good sensitivity of the SOI pixel detector** to Light, X-rays and charged particles. They functioned well as expected.
- We have done **4 MPW** runs. Each run includes 15~25 designs from many institutes.
- In this FY2009, we are scheduling **3 MPW** runs.
- Improving SOI process with Oki Semiconductor Co. Ltd. to improve the performance, and trying 3D integration with ZyCube Co. Ltd.
- we would like to contribute to future particle-physics experiments such as SHLC upgrade, ILC or Super B factory

Backu  
p



# UNIBOND™ Process (1995, France LETI) -> SOITEC

- 1 Initial silicon wafers A & B
- 2 Oxidation of wafer A to create insulating layer
- 3 Smart Cut ion implantation induces formation of an in-depth weakened layer
- 4 Cleaning & bonding wafer A to the handle substrate, wafer B
- 5 Smart Cut - cleavage at the mean ion penetration depth splits off wafer A
- 6 Wafer B undergoes annealing, CMP and touch polish => SOI wafer complete
- 8 Split-off wafer A is recycled, becoming the new wafer A or B



# PD-SOI v.s. FD-SOI

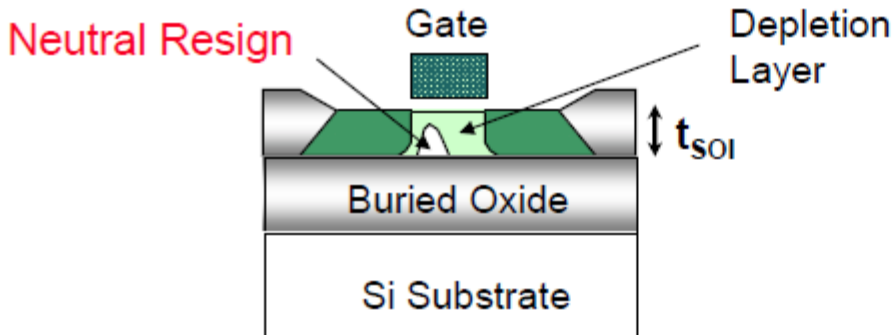
## PD-SOI (Partially Depleted)

◆ Thick SOI thickness ( $T_{SOI}$ )  
~100-200nm

◆ Depletion layer  $< T_{SOI}$



- ◇ Large floating body effect
- ◇ High drive Current by kink effect  
→ High speed application



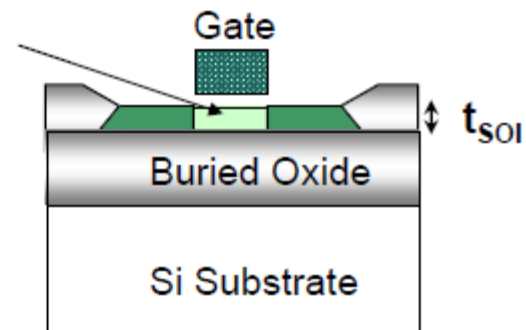
## FD-SOI (Fully Depleted)

◆ Thin SOI thickness ( $T_{SOI}$ )  
< 50nm

◆ Depletion layer  $> T_{SOI}$



- ◇ Less floating body effect
- ◇ Steep subthreshold slopes  
→ Low power application



**FD-SOI has advantage in performance under very low voltage operation.**

# PD-SOI v.s. FD-SOI (2)

## ◆ PD-SOI (Partially Depleted)

High-speed microprocessors

- IBM: PowerPC , mainframe CPU's, Wii(Nintendo), Xbox
- Free scale: PowerPC
- AMD: Athlon processors
- Sony (with IBM and Toshiba) : Cell, PS3



## ◆ FD-SOI (Fully Depleted)

Low-power application

- Oki: solar cell watch, long-wave RF decoder

Technology Node option beyond 32nm, Next 3D Tr.

- Intel, many major companies



<http://www.casio.co.jp>

**At present, only Oki has an experience  
of mass production of FD-SOI**



# CNTPIX3

- 4 kinds of Pixel Block  
216 x 72 (15,552) pixels
- 5.0 x 15.4 mm<sup>2</sup> chip size
- 64 x 64  $\mu\text{m}^2$  pixel size
- Enable Tiling

